

### NDC652P

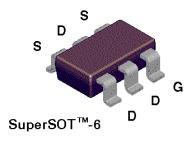
### P-Channel Logic Level Enhancement Mode Field Effect Transistor

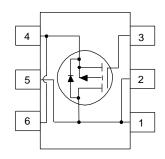
### **General Description**

These P-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast high-side switching, and low in-line power loss are needed in a very small outline surface mount package.

#### **Features**

- Proprietary SuperSOT<sup>TM</sup>-6 package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- Exceptional on-resistance and maximum DC current capability.





Absolute Maximum Ratings	T <sub>A</sub> = 25°C unless otherwise noted
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Symbol	Parameter		NDC652P	Units
V <sub>DSS</sub>	Drain-Source Voltage		-30	V
V <sub>GSS</sub>	Gate-Source Voltage - Continuous		-20	V
I <sub>D</sub>	Drain Current - Continuous		-2.4	А
	- Pulsed		-10	
P <sub>D</sub>	P <sub>D</sub> Maximum Power Dissipation	(Note 1a)	1.6	W
		(Note 1b)	1	
		(Note 1c)	0.8	
$T_J, T_{STG}$	Operating and Storage Temperature	Range	-55 to 150	°C
THERMA	AL CHARACTERISTICS			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Am	bient (Note 1a)	78	°C/W
R <sub>OJC</sub>	Thermal Resistance, Junction-to-Cas	SE (Note 1)	30	°C/W

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	ARACTERISTICS	•			•		
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		-30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, \ V_{GS} = 0 \text{ V}$				1	μA
			$T_J = 55^{\circ}C$			10	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	•			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAI	RACTERISTICS (Note 2)						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-1	-1.5	-3	V
, ,			T <sub>J</sub> = 125°C	-0.7	-1.2	-2.2	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -2.4 \text{ A}$			0.16	0.18	Ω
			T <sub>J</sub> = 125°C		0.22	0.36	
		$V_{GS} = -10 \text{ V}, I_{D} = -3.1 \text{ A}$			0.09	0.11	
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$		-5			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_{D} = -2.4 \text{ A}$			3		S
DYNAMIC	CHARACTERISTICS	<u>.</u>		•		•	
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -15 \text{ V}, \ V_{GS} = 0 \text{ V},$		290		pF	
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz			180		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				60		pF
SWITCHII	NG CHARACTERISTICS (Note 2)						
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DD} = -15 \text{ V}, I_{D} = -1 \text{ A},$			13	20	ns
ţ,	Turn - On Rise Time	$V_{GEN} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$			26	35	ns
t <sub>D(off)</sub>	Turn - Off Delay Time				22	30	ns
f	Turn - Off Fall Time				19	30	ns
$Q_g$	Total Gate Charge	$V_{DS} = -15 \text{ V},$ $I_{D} = -2.4 \text{ A}, V_{GS} = -10 \text{ V}$			10.5	20	nC
$Q_{gs}$	Gate-Source Charge	$I_D = -2.4 \text{ A}, \ V_{GS} = -10 \text{ V}$			1.5		nC
$Q_{gd}$	Gate-Drain Charge				3.3		nC

ELECTRICAL CHARACTERISTICS (T <sub>A</sub> = 25°C unless otherwise noted)										
Symbol	Parameter Conditions Min Typ Max Units									
DRAIN-SO	DRAIN-SOURCE DIODE CHARACTERISTICS									
Is	Continuous Source Diode Current -1.3									
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.3 \text{ A (Note 2)}$		-0.8	-1.2	V				

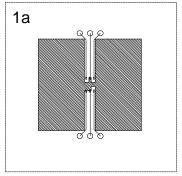
#### Notes:

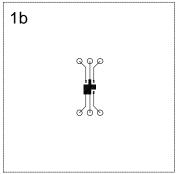
1.  $R_{BJA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{BJC}$  is guaranteed by design while  $R_{BCA}$  is determined by the user's board design.

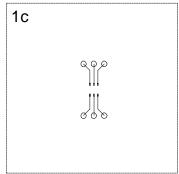
$$P_D(t) = \frac{T_J \cdot T_A}{R_{\theta J} \cdot \hat{k}^{\dagger}} = \frac{T_J \cdot T_A}{R_{\theta J} \cdot \hat{c}^{\dagger} R_{\theta C} \cdot \hat{k}^{\dagger}} = I_D^2(t) \times R_{DS(ON)} g_{TJ}$$

Typical  $R_{\rm g,A}$  using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 78°C/W when mounted on a 1 in² pad of 2oz cpper.
- b. 125°C/W when mounted on a 0.01 in² pad of 2oz cpper.
- c. 156°C/W when mounted on a 0.003 in² pad of 2oz cpper.







Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2.0%.

### **Typical Electrical Characteristics**

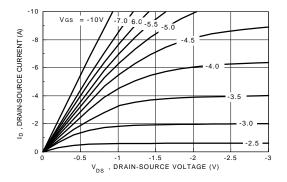


Figure 1. On-Region Characteristics

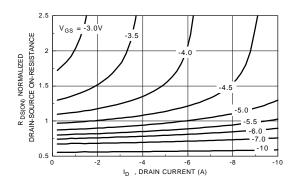


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

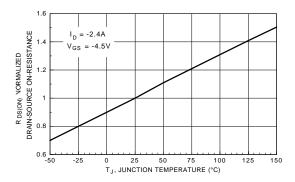


Figure 3. On-Resistance Variation with Temperature

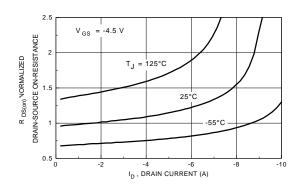


Figure 4. On-Resistance Variation with Drain Current and Temperature

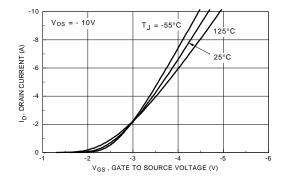


Figure 5. Transfer Characteristics

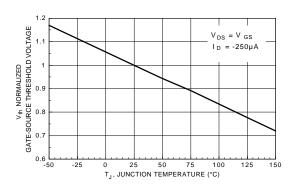


Figure 6. Gate Threshold Variation with Temperature

### **Typical Electrical Characteristics (continued)**

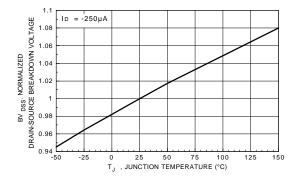


Figure 7. Breakdown Voltage Variation with Temperature

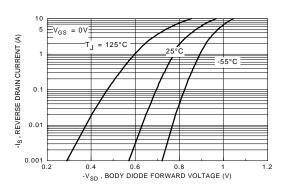


Figure 8. Body Diode Forward Voltage Variation with Source Current and Temperature

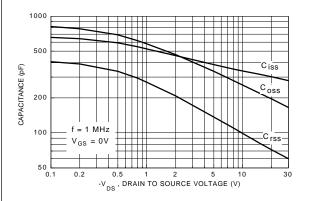


Figure 9. Capacitance Characteristics

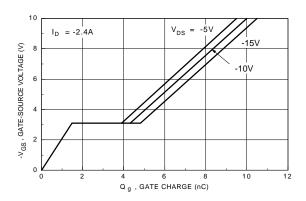


Figure 10. Gate Charge Characteristics

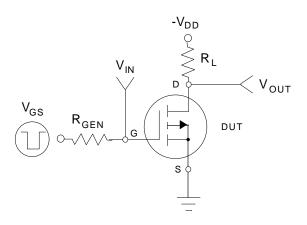


Figure 11. Switching Test Circuit

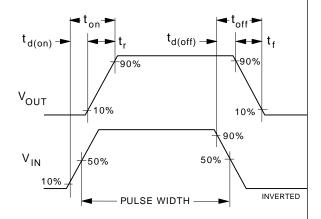
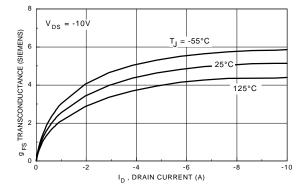


Figure 12. Switching Waveforms

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### Typical Electrical and ThermalCharacteristics (continued)



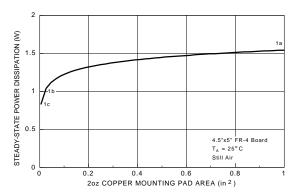
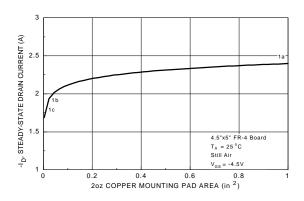


Figure 13. Transconductance Variation with Drain Current and Temperature

Figure 14. SOT-6 Maximum Steady-State Power Dissipation versus Copper Mounting Pad Area.



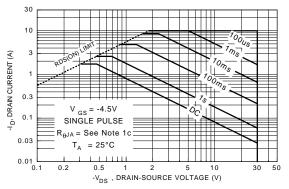


Figure 15. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.

Figure 16. Maximum Safe Operating Area

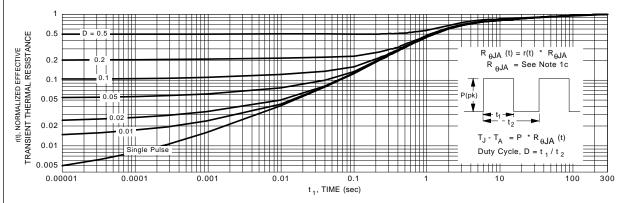
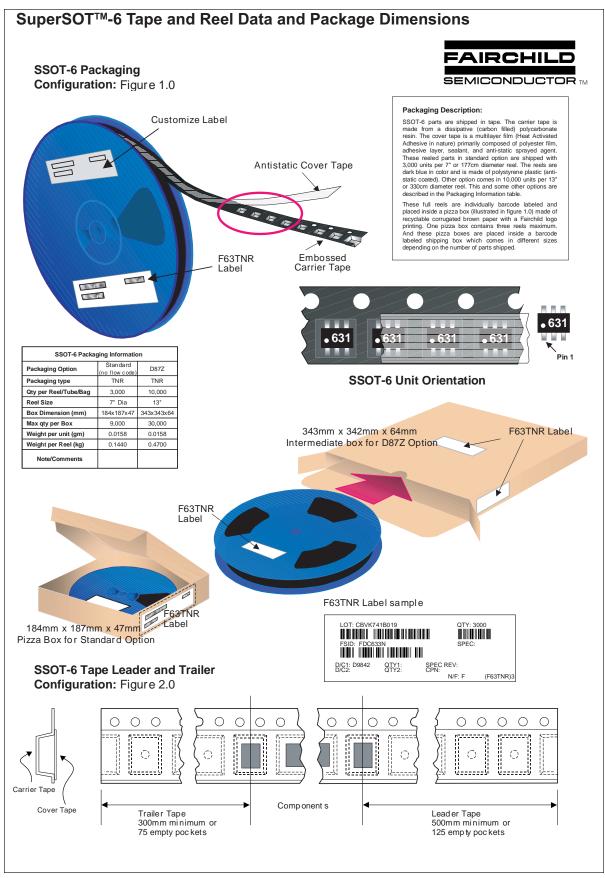
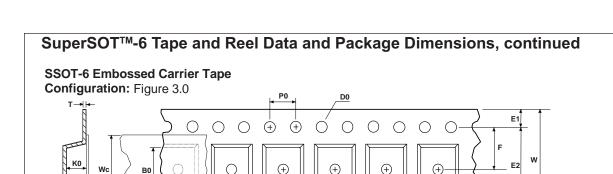


Figure 17. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.

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D1

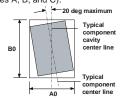
Dimensions are in millimeter														
Pkg type	Α0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	т	Wc	Тс
SSOT-6 (8mm)	3.23 +/-0.10	3.18 +/-0.10	8.0 +/-0.3	1.55 +/-0.05	1.125 +/-0.125	1.75 +/-0.10	6.25 min	3.50 +/-0.05	4.0 +/-0.1	4.0 +/-0.1	1.37 +/-0.10	0.255 +/-0.150	5.2 +/-0.3	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).

A0

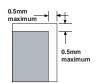


Sketch A (Side or Front Sectional View)
Component Rotation



Sketch B (Top View)

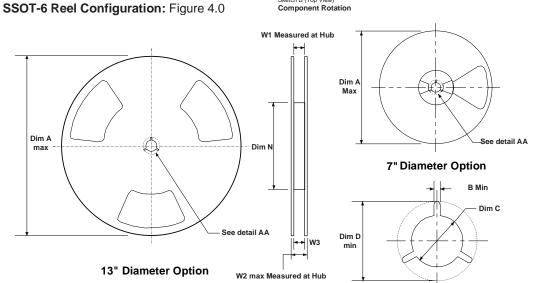
Component Rotation



Sketch C (Top View)

Component lateral movement

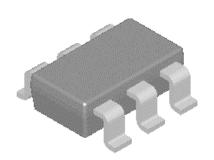
DETAIL AA

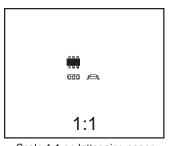


	Dimensions are in inches and millimeters								
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
8mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	2.165 55	0.331 +0.059/-0.000 8.4 +1.5/0	0.567 14.4	0.311 - 0.429 7.9 - 10.9
8mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	4.00 100	0.331 +0.059/-0.000 8.4 +1.5/0	0.567 14.4	0.311 - 0.429 7.9 - 10.9

## SuperSOT™-6 Tape and Reel Data and Package Dimensions, continued

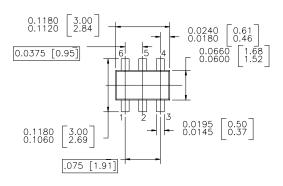
# SuperSOT -6 (FS PKG Code 31, 33)

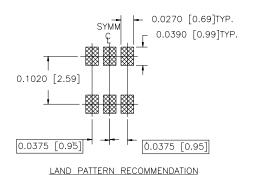




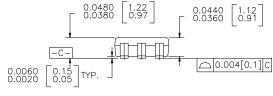
Scale 1:1 on letter size paper
Dimensions shown below are in:
inches [millimeters]

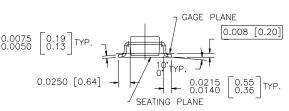
Part Weight per unit (gram): 0.0158





CONTROLLING DIMENSION IS INCH VALUES IN [ ] ARE MILLIMETERS





NOTES: UNLESS OTHERWISE SPECIFIED

1.0 STANDARD LEAD FINISH: 150 MICROINCHES 93.81 MICROMETERS) MINIMUM TIN / LEAD (SOLDER) ON COPPER.

 $2.0\ \mathsf{NO}\ \mathsf{JEDEC}\ \mathsf{REGISTRATION}\ \mathsf{AS}\ \mathsf{OF}\ \mathsf{JULY}\ 1996$ 

SUPER SOT 6 LEADS

September 1998, Rev. A

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 $\begin{array}{lll} \mathsf{FAST}^{\circledast} & \mathsf{Quiet}\,\mathsf{Series^{\mathsf{TM}}} \\ \mathsf{FASTr^{\mathsf{TM}}} & \mathsf{SuperSOT^{\mathsf{TM}}\text{-}3} \\ \mathsf{GTO^{\mathsf{TM}}} & \mathsf{SuperSOT^{\mathsf{TM}}\text{-}6} \\ \mathsf{HiSeC^{\mathsf{TM}}} & \mathsf{SuperSOT^{\mathsf{TM}}\text{-}8} \\ \end{array}$ 

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Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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Rev. D